SDLS194

D2638, JANUARY 1981 - REVISED MARCH 1988

- · 4-Bit Universal Shift Registers/Latches
- Multiplexed Outputs for Shift Register or Latched Data
- Choice of Direct SR Clear ('LS671) or Synchronous SR Clear ('LS672)
- 3-State Outputs Drive Bus Lines Directly
- Expandable to Any Word Length

description

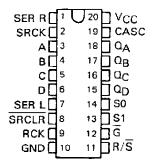
The 'LS671 and 'LS672 each contain a 4-bit universal shift register (similar to the 'LS194A) and a 4-bit storage register (similar to the 'LS175) multiplexed to a 3-state output stage (similar to the 'LS258). The user has the option of selecting the shift or storage register via the register/shift select input R/\$\overline{S}\$. The 'LS671 has a direct-overriding shift register clear while the 'LS672 features a synchronous shift register clear. The shift register has four distinct modes of operation, namely:

Inhibit clock (do nothing)
Shift right (in the direction Q_{Δ} toward Q_{D})
Shift left (in the direction Q_{D} toward Q_{Δ})
Parallel (broadside) load

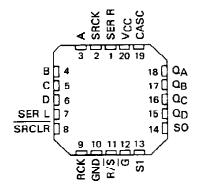
A cascade output for the shift register is provided so that full shift register functionality is provided even while the outputs are in the high-impedance mode. The cascade output presents Q_{Δ} data in the shift-left mode, Q_{D} data in the shift-right mode.

Both the shift register clock and the latch clock are triggered on the positive transition. The output control (\overline{G}) activates Q_{Δ} thru $Q_{\overline{D}}$ when low, it places Q_{Δ} thru $Q_{\overline{D}}$ into the high-impedance state when high.

SN54LS671, SN54LS672 . . . J PACKAGE SN74LS671, SN74LS672 . . . DW OR N PACKAGE (TOP VIEW)



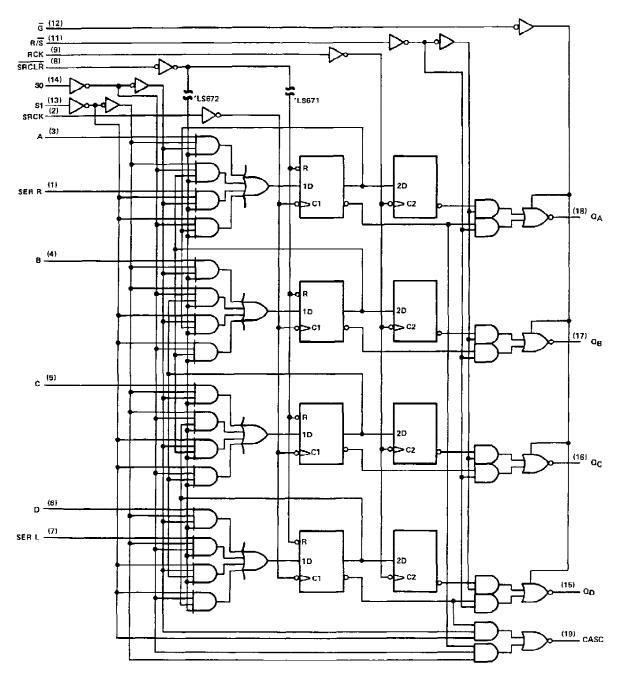
SN54LS671, SN54LS672 . . . FK PACKAGE (TOP VIEW)



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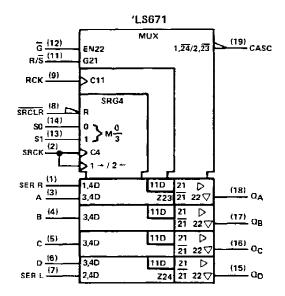


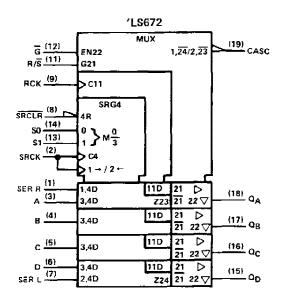
logic diagram (positive logic)



Pin numbers shown are for DW, J and N packages.

logic symbols †





[†]These symbols are in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers shown are for DW, J, and N packages.

FUNCTION TABLE

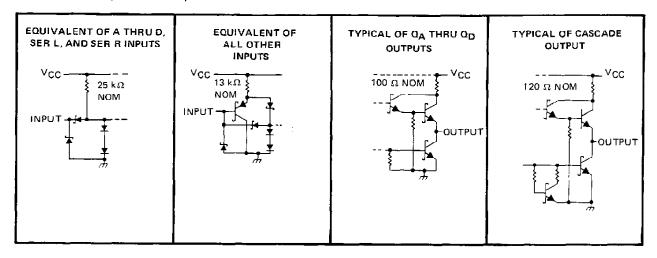
		į			i	SF	CK_	i -	IAL		PARA	ALLEL			PAR	ALLEL					
		SR MODE		R MODE		SR MODE		SR MODE		,rs672	INP	UTS		INF	UTS			OUT	PUTS		
Ğ	R/S	SRCLR	S 1	SO	,rse7	Ţ.	SL	SR	А	8	С	D	QΑ	ag	α _C	αD	CASC [‡]				
L,	L	L	×	×	×	1	х	×	х	×	×	×	L	L	L	L	(‡)				
L	L.	н	×	×	L	L	×	X	х	×	×	X	Δ _{A0}	a_{80}	a_{co}	a_{D0}	(‡)				
L	L	н	L	L	х	х	х	X,	х	Х	×	Х	□ _{A0}	Q _{B0}	o _{C0}	a_{D0}	H				
L	Ł	н	L	н	t	1	х	н	×	X	X	X	н	a_{An}	α_{Bn}	Q _{Cn}	a_{Cn}				
L	L	Н	L	н	†	•	Х	L	х	Х	×	×) L	QAn	a_{Bn}	acn	a_{Cn}				
L	L	н	Н	L	†	t	н	X	X	X	X	×	a _{Bn}	Q_{Cn}	Q_{Dn}	н	QBn				
L	L	н	Н	L	•	t	L	Х	×	x	Χ	х	ΩBn	a_{Cn}	Q_{Dn}	L	a_{Bn}				
L	L	н	Н	н	•	1	Х	×	а	b	C	d	a	b	C	ď	н				
Н	X	×	L	н	f	Ť	Х	х	X	Х	X	Х	z	2	Z	Z	QCn				
H	×	×	Н	L	į	t	X	×	Х	X	X	X	z	2	2	2	Q _{Bn}				
L	H	×	×	×	х	х	Х	х	х	х	Х	Х	Inte	ernal regis	ter conte	nts	(‡)				

When the output control \overline{G} is high, the 3-state outputs are disabled to the high-impedance state; however, sequential operation of the shift register and the output at CASC are not affected.

- H = high level (steady state)
- = low level (steady state)
- X = irrelevant (any input, including transitions)
- † = transition from low to high level
- a, b, c, d = the level of steady-state input at A, B, C, or D, respectively
- QAO, QBO, QCO, QDO = the level of QA, QB, QC, or QD, respectively, before the indicated steady-state input conditions were established QAn, QBn, QCn = the level of QA, QB, or QC, respectively, before the most-recent transition of the clock
- Z = high-impedance state
- The cascade output displays the D bit of the shift register in mode 1 (S1, S0 = L, H), the A bit in mode 2 (S1, S0 = HL), and is inactive (H) in modes 0 and 3 (S1, S0 \Rightarrow LL and HH).



schematics of inputs and outputs



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage VCC (see Note 1)	7 V
Input voitage	7 V
Off-state output voltage	5.5 V
Operating free-air temperature range: SN54LS671, SN54LS672	
Storage temperature range	65°C to 150°C

NOTE 1: Voltage values are with respect to the network ground terminal.

recommended operating conditions

			SN54LS'				UNIT		
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4.5	5	5.5	4.75	5	5.25	V
1	High love) guerrie guerre	Cascade out	1		- 0.4			- 0.4	
IOH	High-level output current	α _A , α _B , α _C , α _D			- 1			- 2.6	mA
1	Low-level output current	Cascade out	 		4			8	mA
OL	Cow-level adibat carrent	Q _A , Q _B , Q _C , Q _D	Ĭ		12			24	""A
tw	Width of SRCK, RCK, or SRC	30			30			ns	
^t su	Inactive state setup time	SRCLR before SRCK † ('LS671 only)	30			30	-		ns
		S0 or S1 to SRCK 1	45			45			
		SRCLR ↓ ('LS672 only) to SRCK ↑	25			25			
t _{su}	Setup time	A, B, C, D to SRCK t	30			30			ns
		SRCK f to RCK f	30			30			
		SER to SRCK 1	35			35			
^t h	Hold time	Any input from SRCK †	0			0			ns
^{T}A	Operating free-air temperature		65		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

				7507.00			SN54LS	,				
	PAHAI	METER		TEST CON	DITIONS	MIN	TYP [‡]	MAX	MIN	TYP [‡]	MAX	UNIT
VIH	High-level input	voltage				2			2			V
VIL	Low-level input	voltage						0.7			0.8	V
Vik	Input clamp voltage			V _{CC} = MIN, I _I	= -18 mA			-1.5			-1.5	V
			$a_A - a_D$	V _{CC} = MIN,	I _{OH} = -1 mA	2.4	3.1					
۷он	High-level outpu	it voltage	$\Omega_A - \Omega_D$	V _{IH} = 2 V,	IOH = -2.6 mA				2.4	3.1		V
			CASC	V _{IL} = V _{IL} max	I _{OH} ≈400 μA	2.5	3.2		2.7	3.2]
			$Q_A - Q_D$		I _{OL} = 12 mA		0.25	0.4		0.25	0.4	
V	Lawland outon	+ voltage	$Q_A = Q_D$	V _{CC} = MIN,	I _{OL} = 24 mA					0.35	0.5	v
VOL	Low-level output voltage		CASC	V _{IH} = 2 V	IOL = 4 mA		0.25	0.4		0.25	0.4	*
			CASC	1	loL - 8 mA					0.35	0.5	
	Off-state output	current,	QA - QD	V _{CC} = MAX,	V _O = 2.7 V,			20			20	μА
OZH	high-level voltage	e applied	QΔ – QD		VIL = VIL max	20		20				
10	Off-state output	Off-state output current, $Q_A - Q_D$			Vo = 0.4 V,		_	-20			-20	μА
IOZL	low-level voltage	applied		V _{IH} = 2 V,	VIL = VIL max			-20			-20	
	Input current at maximum			V _{CC} = MAX,	V. = 7 V			0.1			0,1	mA
'I	input voltage	input voltage		ACC - MVV				0.1	L			
liH .	High-level input	current		V _{CC} = MAX,	V _J = 2.7 V			20			20	μА
Lin	Low-level leavet	current	A, B, C, D	VCC = MAX,	V1 = 0.4 V			- 0.4			-0.4	mA
IIL.	Low-level input current All or			VCC - MAX,	V - 0.4 V			-0.2			-0.2	1112
los	Short-circuit output current \$ QA -			Vcc = MAX,	VO = 0 V	-30		-130	-30		-130	mA
108	Short-chear oatbat can ent »		CASC	√CC - 101 A A ,	*0-0*	-20		-100	-20		-100	
		All outputs I	οw	V _{CC} = MAX,	See Note 2		35	70		35	70	
Icc	Supply current	All outputs h	igh	All outputs	See Note 3		30	65		30	65	mA
		QA thru QD	at Hi-Z	open	See Note 4		37	70		37	70	

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



 $^{^{\}dagger}$ All typical values are at V_{CC} = 5 V, T_{A} = 25°C.

Not more than one output should be shorted at a time and duration of the short-circuit should not exceed and second.

NOTES: 2. I_{CCL} is tested after two 0-V to 4.5 V to 0-V pulses have been applied to \$RCK and RCK while S0 is at 4.5 V and all other inputs are grounded.

^{3,} ICCH is tested after two 4.5-V to 0-V to 4.5 V pulses have been applied to SRCK and RCK while all other inputs are at 4.5 V.

^{4.} ICCZ is tested after two 0-V to 4.5-V to 0-V pulses have been applied to SRCK and RCK while S0 and G are at 4.5 V and all other inputs are grounded.

switching characteristics, VCC = 5 V, TA = 25°C, see note 5

	FROM	TO	TEST CON	DITIONS		'LS67'	1		'LS67	2	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	MODE	LOAD	MIN	TYP	MAX	MIN	TYP	MAX	ONLI	
tPLH	SRCK 1		_			31	45		31	45	ns	
tPHL t	Diter 1		SHIFT LEFT			14	25		14	25		
tPLH	\$0, \$1 SRCK_f	CASCADE	OR RIGHT	$A_L = 2 k\Omega$,		11	20		12	20	ns	
tPHL		0,100,100		CL = 15 pF		11	20		12	20		
tPHL			SR CLEAR		[19	30	ns	
tPHL	\$RCLR ↓		<u> </u>			19	30				ns	
tPLH	SRCK ↑		SHIFTLEFT			10	20		10	20	ns	
tPHL .			OR RIGHT			16	25	<u></u>	16	25	<u> </u>	
^t PLH_			\$R LOAD			10	20		10	20	ns	
tPHL		[011 E07B			15	25		15	25		
tPHL.			SRCLEAR						17	30	ns	
tPHL			011 0 2 2 1 11 1			21	30				กร	
^t PLH	RCK t	QA - QD	LATCH	RL = 667 Ω,	<u> </u>	10	20		10	20	ns	
tPH L	nck i	α <u>д</u> – α _D		C _L = 45 pF		15	25		15	25		
tPLH .	R/S t			i	[12	25		13	25	ns	
tPHL	H/3 1		****	MUX			15	25		15	25]
^t PLH	R/S ↓		MOX			17	25		17	25	ns	
†PHL	H/5 ‡					16	25		16	25] "	
tpZH	Ğ↓	Ì	3-STATE			16	25		16	25	ns	
tPZL .		Į i	ENABLE			19	30		19	30		
tPHZ	<u>G</u> t		3-STATE	RL≖667Ω,		16	25		16	25	ns	
1PLZ	<u> </u>		DISABLE	C <u>L</u> = 5 pF		16	25		16	25] ""	

NOTE 5: Load circuits and voltage waveforms are shown in Section 1.

TYPICAL APPLICATION DATA

The 'LS671 or 'LS672 can easily be expanded utilizing the cascade output and the SER L and SER R inputs. A typical expansion is shown below.

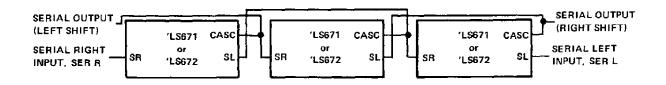


FIGURE 1 - 'LS671, 'LS672 EXPANDED TO 12 BITS, (3 PACKAGES)

Any desired word length may be obtained using the scheme shown. Corresponding control pins of all the packages are tied in common, i.e., all SO pins are connected together, all S1 pins are connected together, etc.



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